

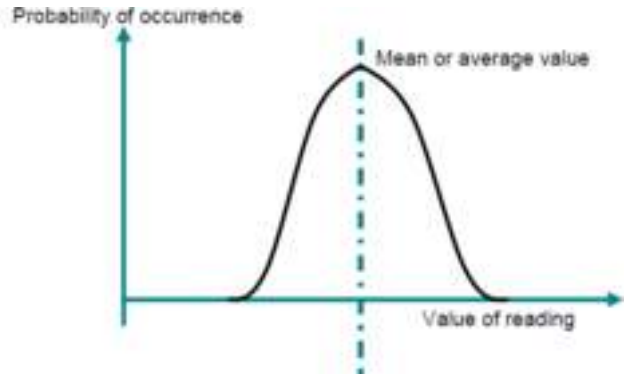
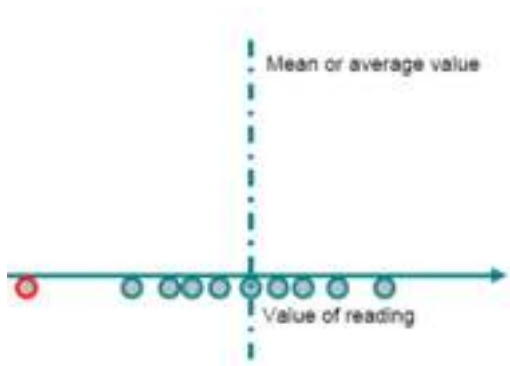
$$U = k \sqrt{U_H^2 + u_{ms}^2 \left( \frac{U_{MPE}}{\sqrt{3}} \right)^2}$$

$$U_H = t \cdot S_H$$

$$S_H = \sqrt{\frac{1}{n-1} \sum_{i=1}^n (H_i - H_{AVG})^2}$$

$$U_{MPE} = E_{rel} \cdot H_{CRM}$$

Type of impact device	Leeb hardness of reference test block	Maximum permissible error (Erel) %
D, D+15	<500	±4.0
DL, S	<700	
C, E	<600	
G	<450	
D, D+15	500 to 700	±3.0
DL, S	700 to 850	
C, E	600 to 750	
G	450 to 600	
D, D+15	>700	±2.0
DL, S	>850	
C, E	>750	
G	>600	



[Terms Of Use](#)  
[Website Data Privacy Policy](#)

**Copyright © 2024 Screening Eagle Technologies. All rights reserved.** The trademarks and logos displayed herein are registered and unregistered trademarks of Screening Eagle Technologies S.A. and/or its affiliates, in Switzerland and certain other countries.